ABSTRACT OF THE DISCLOSURE

A system for WAT (Wafer Acceptance Test) configuration. The system comprises an input/output device, a storage device, and a processor. The input/output device receives a first WAT

5   model and qualification criteria. The storage device stores a preset WAT model and qualification criteria. The processor modifies the preset WAT model according to the first WAT model to generate a second WAT model, and modifies the preset qualification criteria according to the first qualification

10 criteria to generate second qualification criteria.